

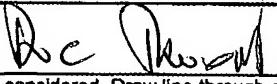
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PATENT & TRADEMARK OFFICE

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14157-011001	Application No. 10/627,353
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Fumio Saitoh et al.		
		Filing Date July 25, 2003	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
W	AA	4,668,448	05/26/87	Weber et al.	264	22	
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes      No
W	AL	0 990 673 A2	04/05/00	EP	G08G	73/22	
	AM	0 172 012	02/19/86	EP	C09K	19/02	
	AN	0 171 017 A2	02/12/86	EP	B29C	67/24	
	AO	7-13168	01/17/95	JP	G02F	1/1337	
	AP	WO 95/19386	07/20/95	WIPO	C08J	5/18	
	AQ	WO 93/23460	11/25/93	WIPO	C08J	5/18	
W	AR	WO 93/06191	04/01/93	WIPO	C09K	19/00	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AS	
	AT	
	AU	
	AV	

Examiner Signature		Date Considered	6/20/04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
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							Yes      No
AK	2001-011311	01/16/01	JP	C08L	79/06		
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